Contents

The S-29430A is high speed, low power 8K-bit serial E²PROM with a wide operating voltage range. It is organized as 512-word × 16-bit. It is capable of sequential read, where addresses are automatically incremented in 16-bit blocks. The instruction code is compatible with the NM93C Series.

■ Features

· Low power consumption
    Standby   : 1 μA Max.
    Operating : 1.2 mA Max. (V_{CC} = 5.5 V)
              : 0.4 mA Max. (V_{CC} = 2.5 V)
· Wide operating voltage range
    Write   : 2.5 to 5.5 V
    Read   : 1.8 to 5.5 V
· Sequential read capable

· Endurance : 10^5 cycles/word
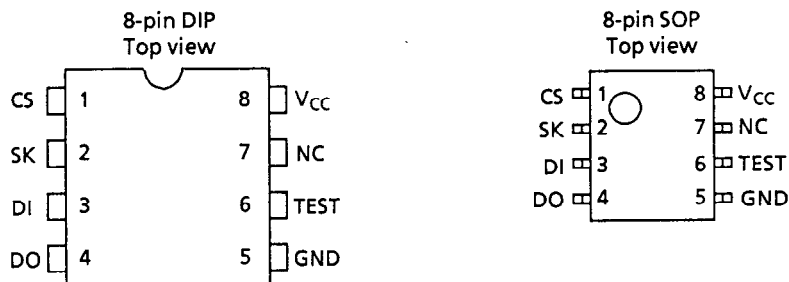· Data retention : 10 years

■ Pin Assignment

8-pin DIP
Top view

CS	1		8	V_{CC}
SK	2		7	NC
DI	3		6	TEST
DO	4		5	GND

8-pin SOP
Top view

CS	1		8	V_{CC}
SK	2		7	NC
DI	3		6	TEST
DO	4		5	GND

Figure 1

CS		Chip select input
SK		Serial clock input
DI		Serial data input
DO		Serial data output
GND	—	Ground (0 V)
V_{CC}		Power supply
TEST		Test pin (normally kept open) (can be connected to GND or Vcc)

■ Block Diagram
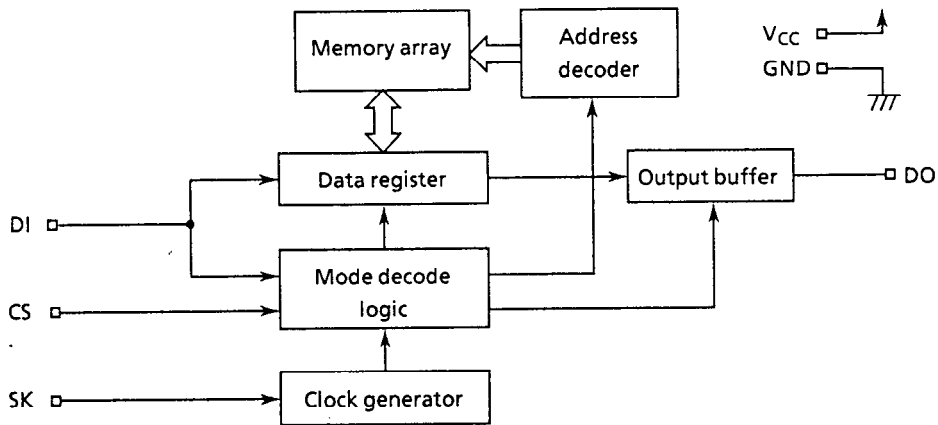
Figure 2

■ Instruction Set

Table 1

Instruction	Start Bit	Ope code	Address	Data
READ (Read data)	1	10	XA_8 to A_0	D_{15} to D_0*
WRITE (Write data)	1	01	XA_8 to A_0	D_{15} to D_0
ERASE (Erase data)	1	11	XA_8 to A_0	—
EWEN (Program enable)	1	00	11xxxxxxxx	—
EWDS (Program disable)	1	00	00xxxxxxxx	—

x : Doesn't matter.

* : When 16-bit data of the specified address is output, the data of the next address is output.

■ Absolute Maximum Ratings

Table 2

Parameter	Symbol	Ratings	Unit
Power supply voltage	V_{CC}	-0.3 to + 7.0	V
Input voltage	V_{IN}	-0.3 to V_{CC} + 0.3	V
Output voltage	V_{OUT}	-0.3 to V_{CC}	V
Storage temperature under bias	T_{bias}	-50 to + 95	°C
Storage temperature	T_{stg}	-65 to + 150	°C

■ Recommended Operating Conditions

Table 3

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Power supply voltage	V_{CC}	Read Operation	1.8	—	5.5	V
		Write Operation	2.5	—	5.5	V
High level input voltage	V_{IH}	V_{CC} = 2.5 to 5.5V	$0.8 \times V_{CC}$	—	V_{CC}	V
		V_{CC} = 1.8 to 2.5V	$0.8 \times V_{CC}$	—	V_{CC}	V
Low level input voltage	V_{IL}	V_{CC} = 2.5 to 5.5V	0.0	—	$0.2 \times V_{CC}$	V
		V_{CC} = 1.8 to 2.5V	0.0	—	$0.15 \times V_{CC}$	V
Operating temperature	T_{opr}		-40	—	+85	°C

■ DC Electrical Characteristics

Table 4

Parameter	Symbol	Conditions	V_{CC} = 5.0 V ± 10 %			V_{CC} = 2.5 to 3.3 V			V_{CC} = 1.8 to 2.5 V			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
Current consumption (READ)	I_{CC1}	DO unloaded	—	—	1.2	—	—	0.5	—	—	0.4	mA
Current consumption (PROGRAM)	I_{CC2}	DO unloaded	—	—	5.0	—	—	2.0	—	—	—	mA

Table 5

Parameter	Symbol	Conditions	V_{CC} = 5.0 V ± 10 %			V_{CC} = 2.5 to 4.5 V			V_{CC} = 1.8 to 2.5 V			Unit
			Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
Standby current consumption	I_{SB}	Input: V_{CC} or GND	—	—	1.0	—	—	1.0	—	—	1.0	μA
Input leakage current	I_{LI}	V_{IN} = GND to V_{CC}	—	0.1	1.0	—	0.1	1.0	—	0.1	1.0	μA
Output leakage current	I_{LO}	V_{OUT} = GND to V_{CC}	—	0.1	1.0	—	0.1	1.0	—	0.1	1.0	μA
Low level output voltage	V_{OL}	CMOS I_{OL} = 100 μA	—	—	0.1	—	—	0.1	—	—	0.1	V
		TTL I_{OL} = 2.1 mA	—	—	0.45	—	—	—	—	—	—	V
High level output voltage	V_{OH}	CMOS V_{CC} = 2.5 to 5.5 V : I_{OH} = -100 μA V_{CC} = 1.8 to 2.5 V : I_{OH} = -10 μA	V_{CC}-0.7	—	—	V_{CC}-0.7	—	—	V_{CC}-0.3	—	—	V
		TTL, I_{OH} = -400 μA	2.4	—	—	—	—	—	—	—	—	V
Write enable latch data hold voltage	V_{DH}		1.5	—	—	1.5	—	—	1.5	—	—	V

■ Endurance

Table 6

Parameter	Symbol	Min.	Typ.	Max.	Unit
Endurance	N_W	10^5	—	—	cycles/word

■ Pin Capacitance

Table 7

(Ta = 25°C, f = 1.0 MHz, V_{CC} = 5 V)

| Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Input Capacitance	C_{IN}	V_{IN} = 0 V	—	—	8	pF
Output Capacitance	C_{OUT}	V_{OUT} = 0 V	—	—	10	pF

■ **AC Electrical Characteristics**

Table 8 Measuring conditions

Input pulse voltage	$0.1 \times V_{CC}$ to $0.9 \times V_{CC}$
Output reference voltage	$0.5 \times V_{CC}$
Output load	100pF

Table 9

Parameter	Symbol	Read/Write operations						Read operation			Unit
		$V_{CC} = 5.0\ V \pm 10\ \%$			$V_{CC} = 2.5$ to $4.5\ V$			$V_{CC} = 1.8$ to $2.5\ V$			
		Min.	Typ.	Max.	Min.	Typ.	Max.	Min.	Typ.	Max.	
CS setup time	t_{CSS}	0.2	—	—	0.4	—	—	1.0	—	—	μs
CS hold time	t_{CSH}	0.2	—	—	0.4	—	—	1.0	—	—	μs
CS setup time (CPU)	$t_{CSS\,(CPU)}$	0.2	—	—	0.4	—	—	1.0	—	—	μs
CS hold time (CPU)	$t_{CSH\,(CPU)}$	0.2	—	—	0.4	—	—	1.0	—	—	μs
CS deselect time	t_{CDS}	0.2	—	—	0.2	—	—	0.4	—	—	μs
Data setup time	t_{DS}	0.2	—	—	0.4	—	—	0.8	—	—	μs
Data hold time	t_{DH}	0.2	—	—	0.4	—	—	0.8	—	—	μs
1 data output delay time	t_{PD1}	—	—	0.4	—	—	0.8	—	—	2.0	μs
0 data output delay time	t_{PD0}	—	—	0.4	—	—	0.8	—	—	2.0	μs
Clock frequency	f_{SK}	0.0	—	2.0	0.0	—	0.5	0.0	—	0.2	MHz
Clock pulse width	t_{SKH}, t_{SKL}	0.25	—	—	1.0	—	—	2.5	—	—	μs
Output disable time	t_{HZ1}, t_{HZ2}	0	50	150	0	500	1000	—	—	—	ns
Output enable time	t_{SV}	0	50	150	0	500	1000	—	—	—	ns
Programming time	t_{PR}	—	4.0	10	—	4.0	10	—	—	—	ms
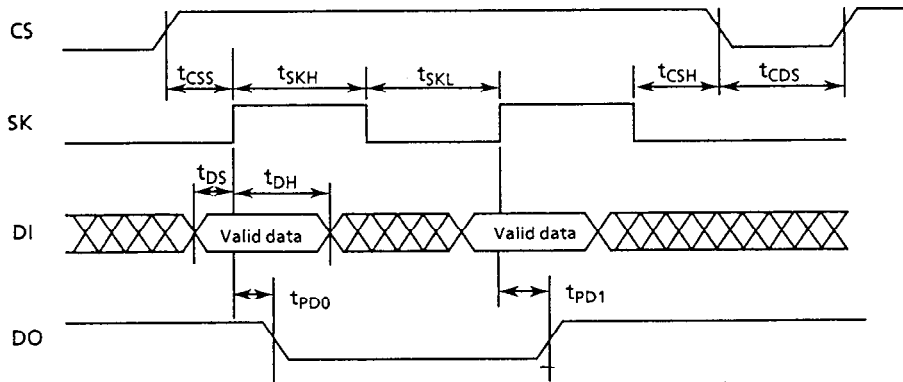
Input data is retrieved on the rising edge of SK.
Output data is triggered on the rising edge of SK.

Figure 3 Timing Chart
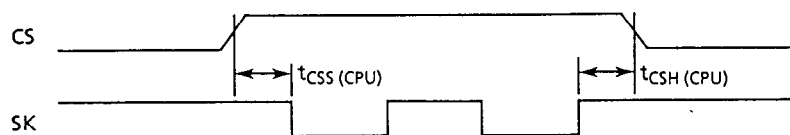
Figure 4 Timing Chart for $t_{CSS\,(CPU)}$ and $t_{CSH\,(CPU)}$ when CPU is connected

■ Operation

Instructions (in the order of start-bit, instruction, address, and data) are latched to DI in synchronization with the rising edge of SK after CS goes high. A start-bit can only be recognized when the high of DI is latched at the rising edge of SK after changing CS to high, it is impossible for it to be recognized as long as DI is low, even if there are SK pulses after CS goes high. Any SK pulses input while DI is low before receiving a start-bit are called "dummy clocks." The number of clocks transmitted by the serial interface in a CPU and the number of clocks needed for operation of the serial memory IC can be adjusted by inserting several dummy clocks before a start-bit. Instruction finishes when CS goes low, where it must be low between commands during t_{CDS}.

All input, including DI and SK signals, is ignored while CS is low.

1. Read

The READ instruction reads data from a specified address. After A0 is latched at the rising edge of SK, DO output changes from a high-impedance state (Hi-Z) to low level output. 16-bit data is continuously output in synchronization with the rise of SK.

When all of the data (D_{15} to D_0) in the specified address has been read, addresses are automatically incremented and the data in the next address can be read with the input of another SK clock. Thus, the data over whole area of the memory can be read by continuously inputting SK clocks as long as CS is high.

The last address (An ⋯ A1 A0 = 1 ⋯ 11) rolls over to the top address (An ⋯ A1 A0 = 0 ⋯ 00).
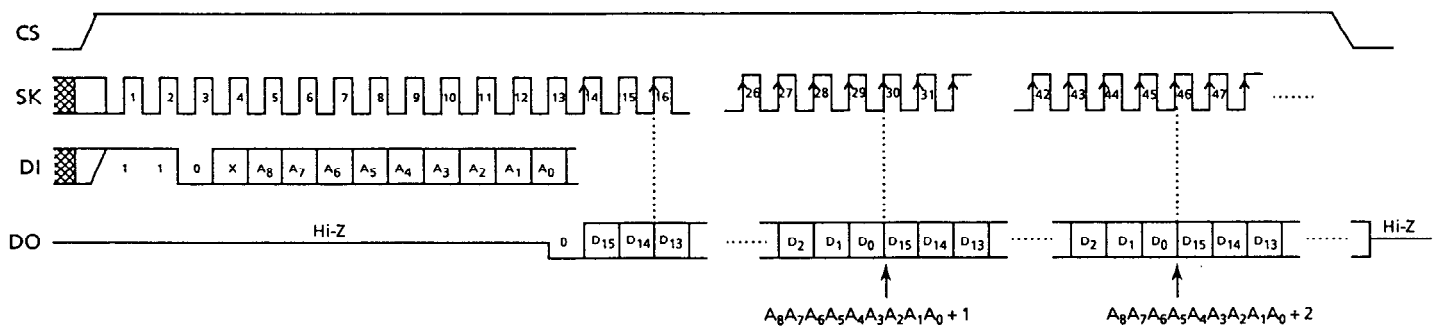
X : Option

Figure 5 Read Timing

2. Write (WRITE, ERASE)

There are two write instructions, WRITE, ERASE. Each automatically begins writing to the non-volatile memory when CS goes low at the completion of the specified clock input.

The write operation is completed in 10 ms (t_{PR} Max.), and the typical write period is less than 5 ms. In the S-29430A Series, it is easy to VERIFY the completion of the write operation in order to minimize the write cycle by setting CS to"H" and checking the DO pin after the write operation begins by setting CS to "L." VERIFY operations to detect changes in the DO output can be executed in succession. One is a change from "L" to "H" with CS = "H." The other is a change from "L" to "H" after setting CS to "H" and returning CS to "L" repeatedly.

Because all SK and DI inputs are ignored during the write operation, any input of instruction will also be disregarded. When DO outputs high after completion of the write operation or if it is in the high-impedance state (Hi-Z), the input of instructions is available. Even if the DO pin remains high, it will enter the high-impedance state upon the recognition of a high of DI (start-bit) attached to the rising edge of an SK pulse.

2.1 WRITE

This instruction writes 16-bit data to a specified address.

After changing CS to high, input a start-bit, op-code (WRITE), address, and 16-bit data. If there is a data overflow of more than 16 bits, only the last 16-bits of the data is considered valid. Changing CS to low will start the WRITE operation. It is not necessary to make the data "1" before initiating the WRITE operation.
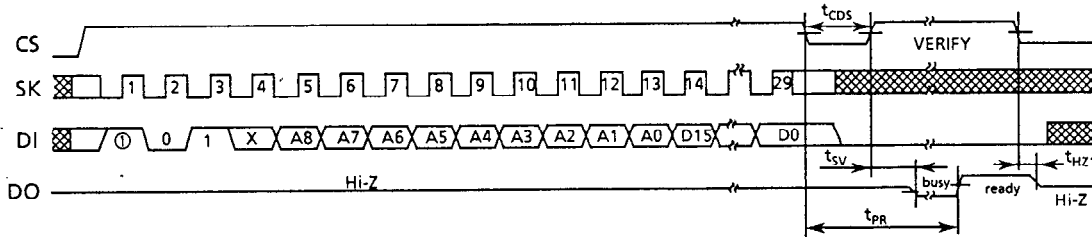

Figure 6 WRITE Timing

2.2 ERASE

This command erases 16-bit data in a specified address.

After changing CS to high, input a start-bit, op-code (ERASE), and address. It is not necessary to input data. Changing CS to low will start the ERASE operation, which changes every bit of the 16 bit data to "1."
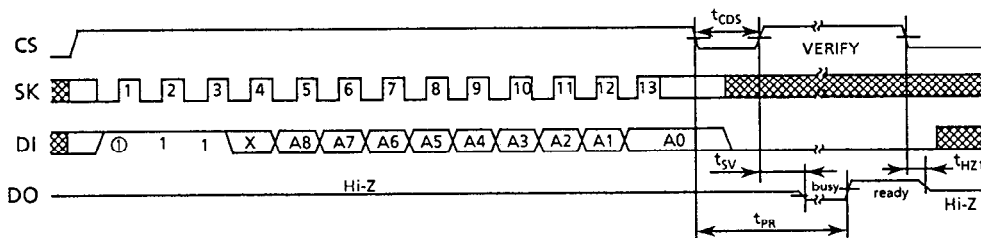
Figure 7 ERASE Timing

3. Write enable (EWEN) and Write disable (EWDS)

The EWEN instruction puts the S-29430A into write enable mode, which accepts WRITE, ERASE instructions. The EWDS instruction puts the S-29430A into write disable mode, which refuses WRITE, ERASE instructions. The S-29430A powers on in write disable mode, which protects data against unexpected, erroneous write operations caused by noise and/or CPU malfunctions. It should be kept in write disable mode except when performing write operations.
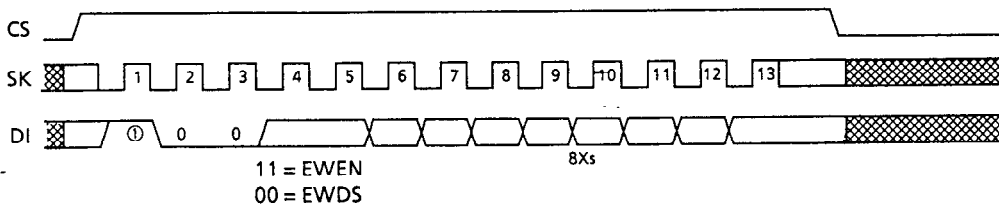
Figure 8 EWEN/EWDS Timing

6

■ **Receiving a Start-Bit**

A start-bit can be recognized by latching the high level of DI at the rising edge of SK after changing CS to high (Start-Bit Recognition). The write operation begins by inputting the write instruction and setting CS to low. The DO pin then outputs low during the write operation and high at its completion by setting CS to high (Verify Operation). Therefore, only after a write operation, in order to accept the next command by having CS go high, the DO pin is switched from a state of high-impedance to a state of data output; but if it recognizes a start-bit, the DO pin returns to a state of high-impedance (see Figure 9).

Make sure that data output from the CPU does not interfere with the data output from the serial memory IC when you configure a 3-wire interface by connecting DI input pin and DO output pin. Such interference may cause a start-bit fetch problem.
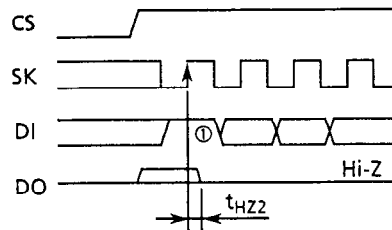
Figure 9 Start bit latching timing

■ **Three-wire Interface (DI-DO direct connection)**

Although the normal configuration of a serial interface is a 4-wire interface to CS, SK, DI, and DO, a 3-wire interface is also a possibility by connecting DI and DO. However, since there is a possibility that the DO output from the serial memory IC will interfere with the data output from the CPU with a 3-wire interface, install a resistor between DI and DO in order to give preference to data output from the CPU to DI (See Figure 10).
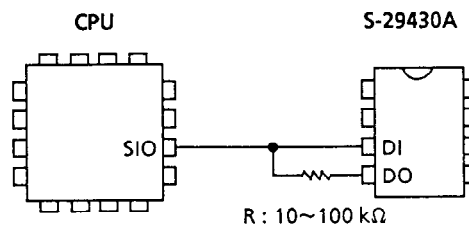
Figure 10 3-wire interface

■ Dimensions (Unit : mm)

1. 8-pin DIP
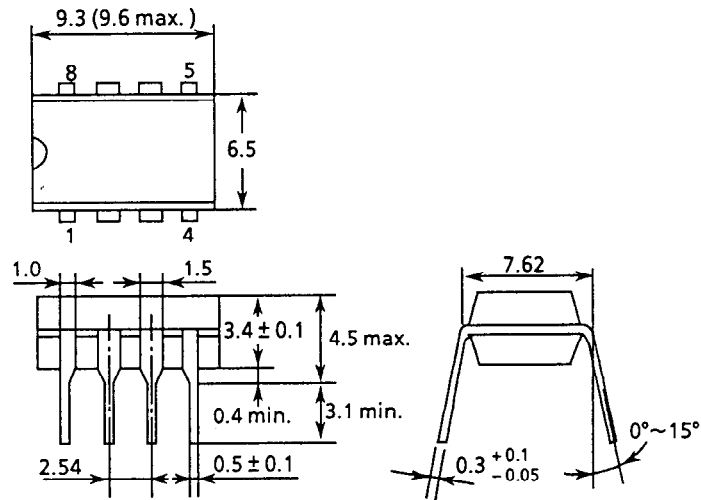
Figure 11

2. 8-pin SOP
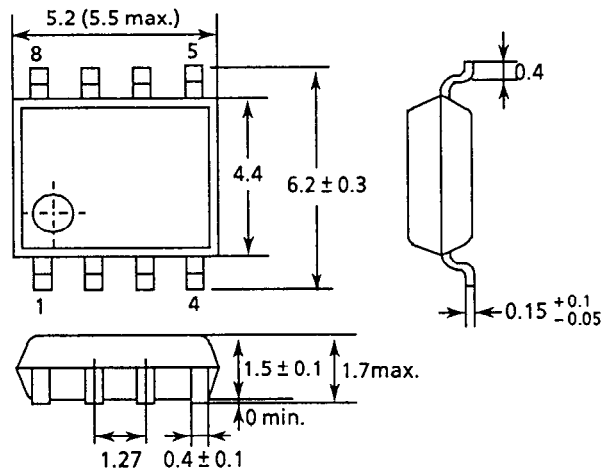
Figure 12

■ Ordering Information

S-29430A XX

Package   DP : DIP
               FE : SOP

8

■ **Characteristics**

1. DC Characteristics

1.1 Current consumption (READ) I_{CC1} — Ambient temperature Ta

$V_{CC} = 5.5V$
$f_{SK} = 2\,MHz$
DATA = 0101

I_{CC1} (mA)

Ta (°C)

1.2 Current consumption (READ) I_{CC1} — Ambient temperature Ta

$V_{CC} = 3.3V$
$f_{SK} = 1MHz$
DATA = 0101

I_{CC1} (mA)

Ta (°C)
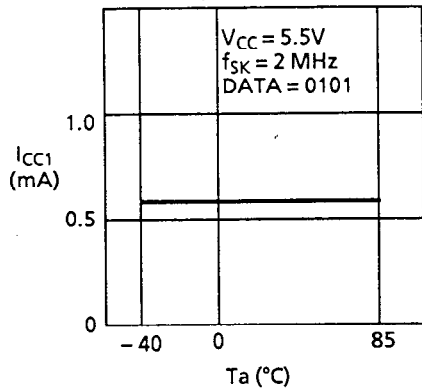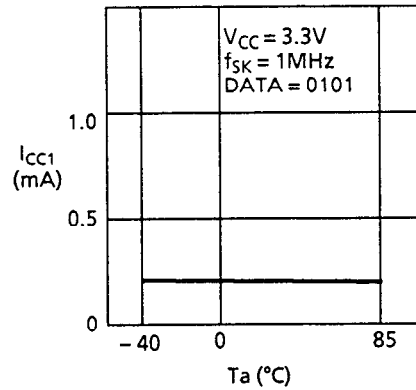
1.3 Current consumption (READ) I_{CC1} — Power supply voltage V_{CC}

Ta = 25°C
$f_{SK} = 1\,MHz$
DATA = 0101

I_{CC1} (mA)

V_{CC} (V)
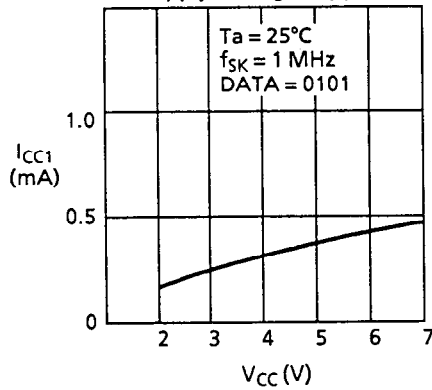
1.4 Current consumption (READ) I_{CC1} — Clock frequency f_{sk}
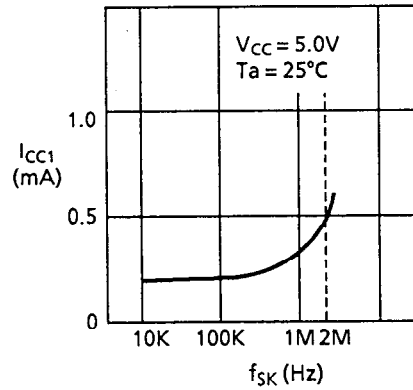
$V_{CC} = 5.0V$
Ta = 25°C

I_{CC1} (mA)

f_{SK} (Hz)

1.5 Current consumption (PROGRAM) I_{CC2} — Ambient temperature Ta

$V_{CC} = 5.5V$
DATA 00000000

I_{CC2} (mA)

Ta (°C)

1.6 Current consumption (PROGRAM) I_{CC2} — Ambient temperature Ta

$V_{CC} = 3.3V$
DATA 00000000

I_{CC2} (mA)

Ta (°C)
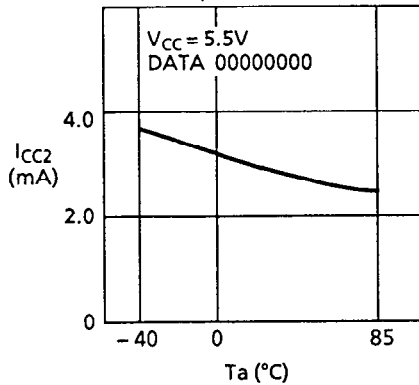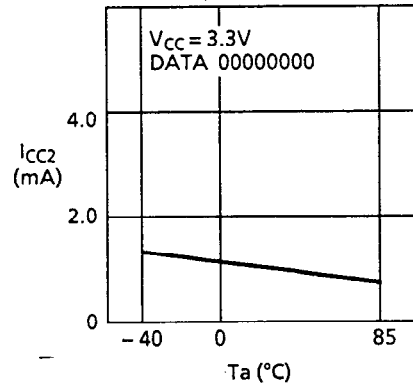
1.7 Current consumption (PROGRAM) I_{CC2} — Power supply voltage V_{CC}

Ta = 25°C
DATA 00000000

I_{CC2} (mA)

V_{CC} (V)
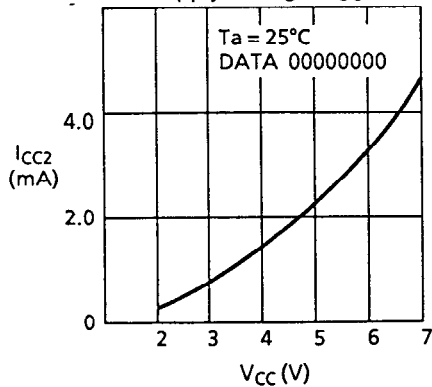
1.8 Standby current consumption I_{SB} — Ambient temperature Ta
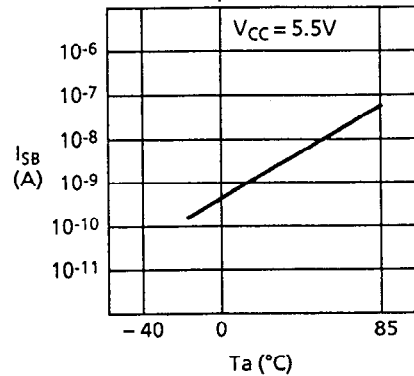
$V_{CC} = 5.5V$

I_{SB} (A)

Ta (°C)

1.9 Input leakage current I_{LI} – Ambient temperature Ta
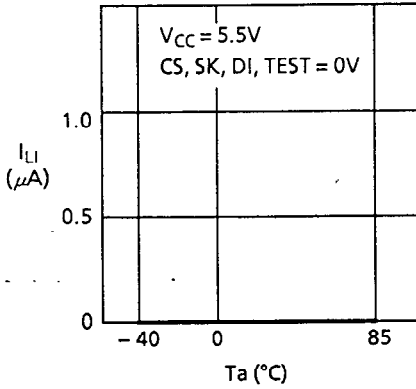
$V_{CC} = 5.5V$
CS, SK, DI, TEST = 0V

I_{LI} (μA)

1.0

0.5

0

−40 0 85

Ta (°C)

1.10 Input leakage current I_{LI} – Ambient temperature Ta

$V_{CC} = 5.5V$
CS, SK, DI, TEST = 5.5V

I_{LI} (μA)

1.0

0.5

0

−40 0 85

Ta (°C)

1.11 Output leakage current I_{LO} – Ambient temperature Ta

$V_{CC} = 5.5V$
DO = 0V

I_{LO} (μA)

1.0

0.5

0

−40 0 85

Ta (°C)

1.12 Output leakage current I_{LO} – Ambient temperature Ta

$V_{CC} = 5.5V$
DO = 5.5V

I_{LO} (μA)

1.0

0.5

0

−40 0 85

Ta (°C)

1.13 High level output voltage V_{OH} – Ambient temperature Ta

$V_{CC} = 4.5V$
$I_{OH} = -400\mu$A

V_{OH} (V)

4.6

4.4

4.2

−40 0 85

Ta (°C)

1.14 High level output voltage V_{OH} – Ambient temperature Ta

$V_{CC} = 2.7V$
$I_{OH} = -100\mu$A

V_{OH} (V)

2.7

2.6

2.5

−40 0 85

Ta (°C)

1.15 Low level output voltage V_{OL} – Ambient temperature Ta

$V_{CC} = 4.5V$
$I_{OL} = 2.1mA$

V_{OL} (V)

0.3

0.2

0.1

−40 0 85

Ta (°C)

1.16 Low level output voltage V_{OL} – Ambient temperature Ta

$V_{CC} = 1.8V$
$I_{OL} = 100\mu$A

V_{OL} (V)

0.03

0.02

0.01

−40 0 85

Ta (°C)
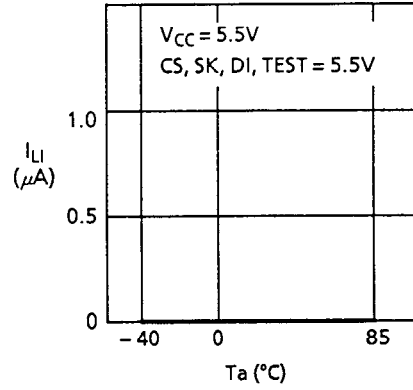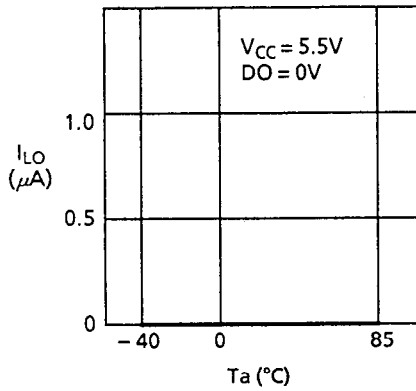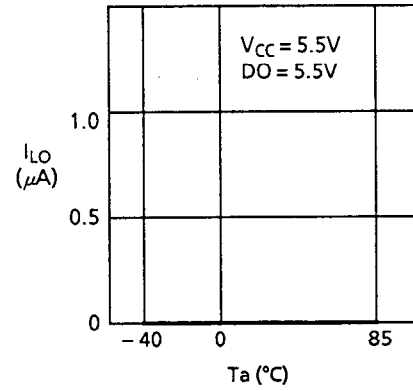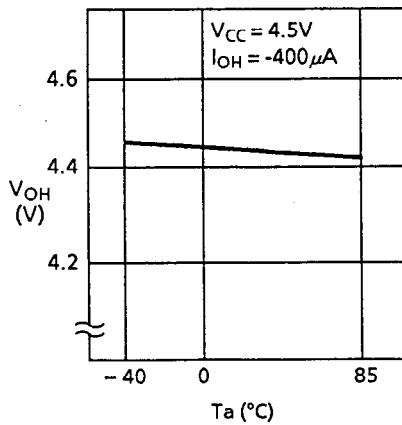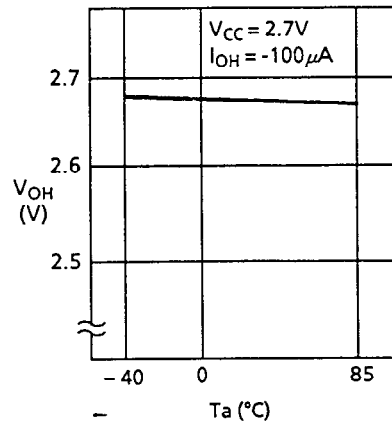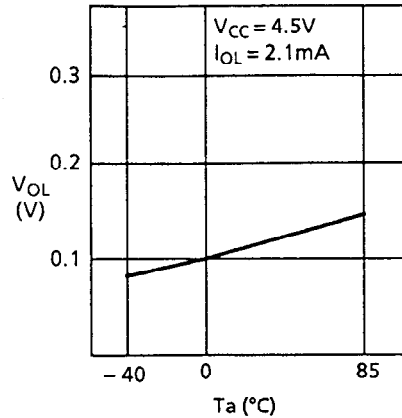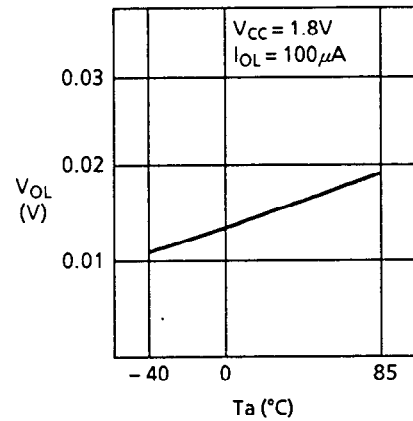
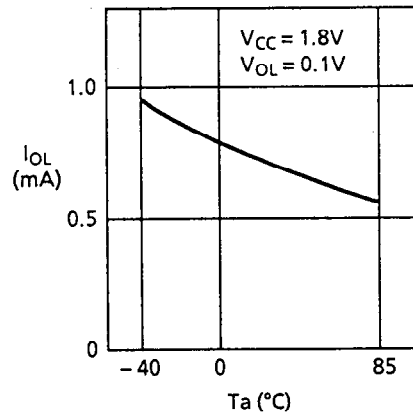1.17 High level output current I_{OH} – Ambient temperature Ta
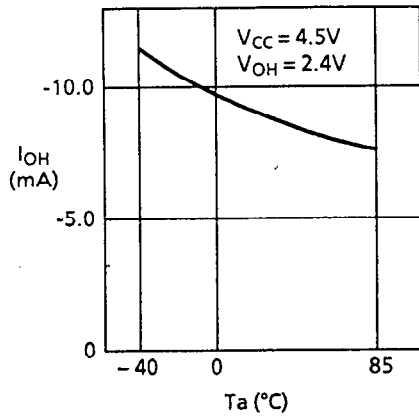
1.18 High level output current I_{OH} – Ambient temperature Ta
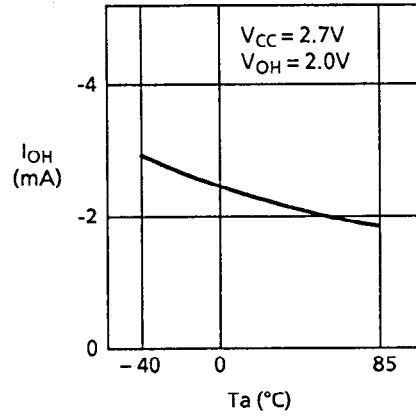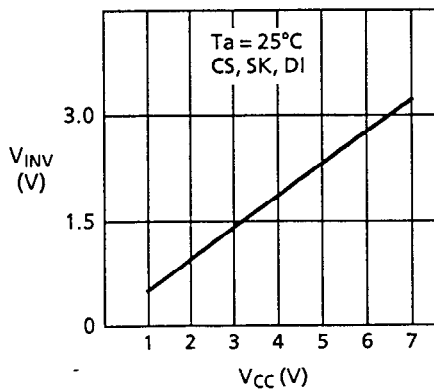

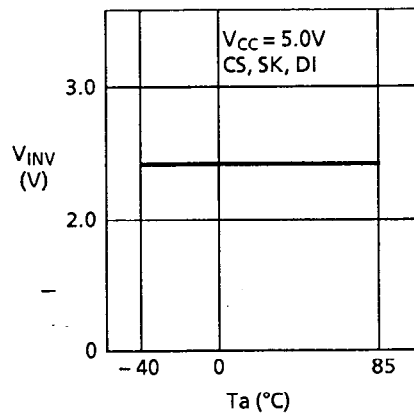1.19 Low level output current I_{OL} – Ambient temperature Ta
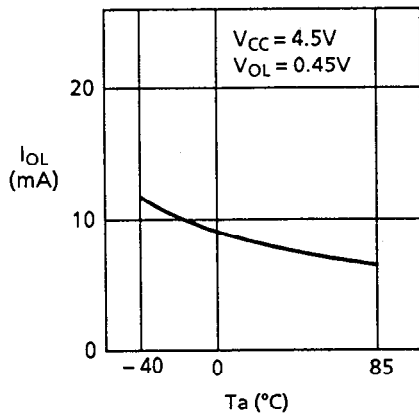
1.20 Low level output current I_{OL} – Ambient temperature Ta

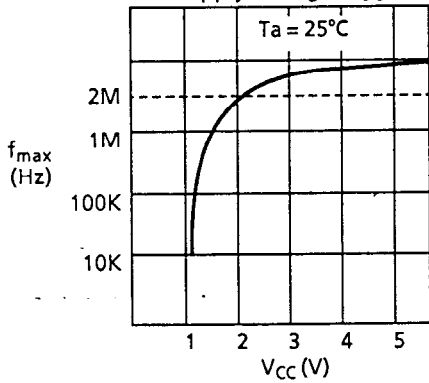1.21 Input inversion voltage V_{INV} – Power supply voltage V_{CC}

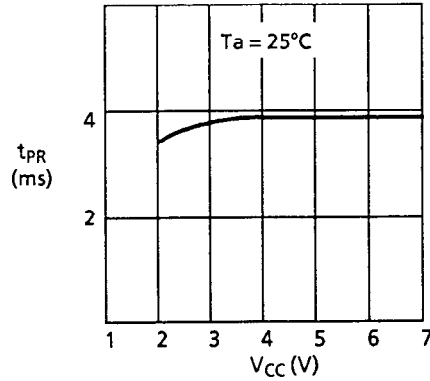1.22 Input inversion voltage V_{INV} – Ambient temperature Ta
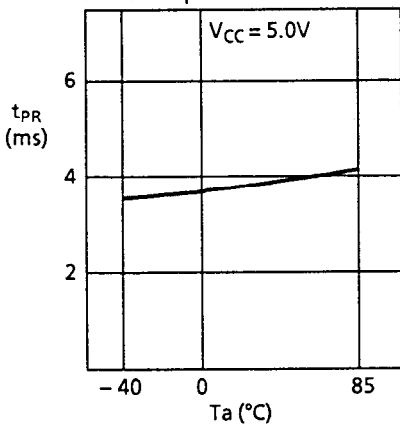
2. AC Characteristics

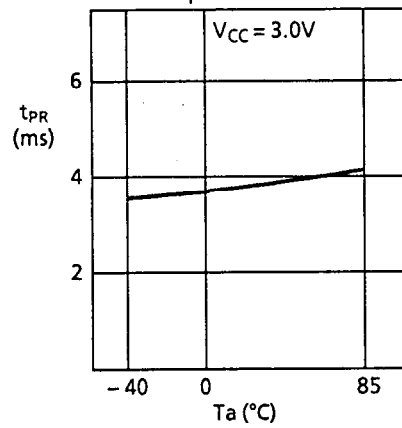### 2.1 Maximum operating frequency f_{max} – Power supply voltage V_{CC}

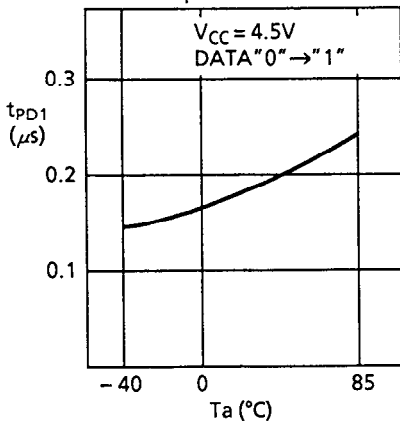### 2.2 Program time t_{PR} – Power supply voltage V_{CC}

2.3 Program time t_{PR} – Ambient temperature Ta
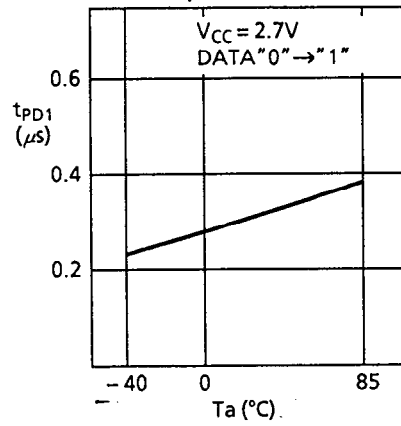

2.4 Program time t_{PR} – Ambient temperature Ta
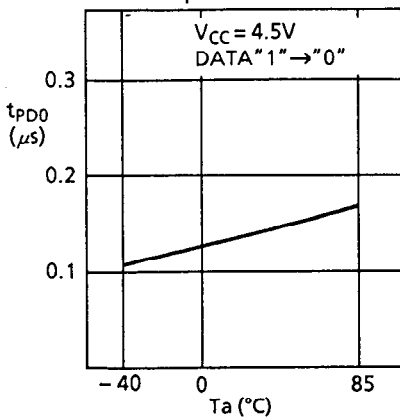

2.5 "1" Data output delay time t_{PD1} – Ambient temperature Ta

2.6 "1" Data output delay time t_{PD1} – Ambient temperature Ta

2.7 "0" Data output delay time t_{PD0} – Ambient temperature Ta

2.8 "0" Data output delay time t_{PD0} – Ambient temperature Ta